

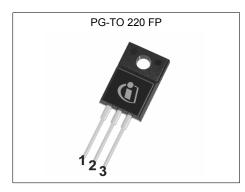
## **MOSFET**

## 700V CoolMOS™ P7 Power Device

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies.

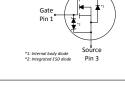
The latest CoolMOS™ P7 is an optimized platform tailored to target cost sensitive applications in consumer markets such as charger, adapter, lighting, TV, etc.

The new series provides all the benefits of a fast switching Superjunction MOSFET, combined with an excellent price/performance ratio and state of the art ease-of-use level. The technology meets highest efficiency standards and supports high power density, enabling customers going towards very slim designs.



### **Features**

- Extremely low losses due to very low FOM R<sub>DS(on)</sub>\*Q<sub>q</sub> and R<sub>DS(on)</sub>\*E<sub>oss</sub>
- Excellent thermal behavior
- Integrated ESD protection diode
- Low switching losses (E<sub>oss</sub>)
- Product validation acc. JEDEC Standard



### **Benefits**

- · Cost competitive technology
- Lower temperature
- High ESD ruggedness
- Enables efficiency gains at higher switching frequencies
- Enables high power density designs and small form factors







## Potential applications

Recommended for Flyback topologies for example used in Chargers, Adapters, Lighting Applications, etc.

#### **Product validation**

Qualified according to JEDEC Standard

Please note: For MOSFET paralleling the use of ferrite beads on the gate or seperate totem poles is generally recommended.

Table 1 Key Performance Parameters

Parameter	Value	Unit	
V <sub>DS</sub> @ T <sub>j=25°C</sub>	700	V	
R <sub>DS(on),max</sub>	0.6	Ω	
$Q_{g,typ}$	10.5	nC	
I <sub>D,pulse</sub>	20.5	A	
E <sub>oss</sub> @ 400V	1.2	μJ	
$V_{(GS)th,typ}$	3	V	
ESD class (HBM)	2		

Type / Ordering Code	Package	Marking	Related Links
IPA70R600P7S	PG-TO 220 FullPAK	70S600P7	see Appendix A



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# 1 Maximum ratings at $T_j = 25$ °C, unless otherwise specified

Maximum ratings Table 2

Danamatan	Oh a l		Value	s	11!4	Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	-	-	8.5 5.0	А	T <sub>C</sub> = 20°C T <sub>C</sub> = 100°C
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	-	-	20.5	Α	T <sub>C</sub> =25°C
Application (Flyback) relevant avalanche current, single pulse <sup>3)</sup>	I <sub>AS</sub>	-	-	3.2	A	measured with standard leakage inductance of transformer of 7μH
MOSFET dv/dt ruggedness	dv/dt	-	-	100	V/ns	V <sub>DS</sub> =0400V
Gate source voltage	V <sub>GS</sub>	-16 -30	-	16 30	V	static; AC (f>1 Hz)
Power dissipation	P <sub>tot</sub>	-	-	24.9	W	<i>T</i> <sub>C</sub> =25°C
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-40	-	150	°C	-
Continuous diode forward current	I <sub>S</sub>	-	-	4.5	Α	<i>T</i> <sub>C</sub> =25°C
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>	-	-	20.5	Α	T <sub>C</sub> = 25°C
Reverse diode dv/dt <sup>4)</sup>	dv/dt	-	-	1	V/ns	V <sub>DS</sub> =0400V, I <sub>SD</sub> <=I <sub>S</sub> , T <sub>j</sub> =25°C
Maximum diode commutation speed <sup>4)</sup>	di <sub>f</sub> /dt	-	-	50	A/μs	V <sub>DS</sub> =0400V, I <sub>SD</sub> <=I <sub>S</sub> , T <sub>j</sub> =25°C
Insulation withstand voltage	V <sub>ISO</sub>	-	-	2500	V	V <sub>rms</sub> , T <sub>C</sub> =25°C, t=1min

#### 2 Thermal characteristics

Table 3 **Thermal characteristics** 

Doromotor	Cumbal		Values	;	l lmi4	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Thermal resistance, junction	R <sub>thJC</sub>	-	-	5.0	°C/W	-
Thermal resistance, junction - ambient		-	-	80	°C/W	leaded
Thermal resistance, junction - ambient for SMD version	R <sub>thJA</sub>	-	-	-	°C/W	n.a.
Soldering temperature, wavesoldering only allowed at leads	T <sub>sold</sub>	-	-	260	°C	1.6 mm (0.063 in.) from case for 10s

 $<sup>^{1)}</sup>$  DPAK / IPAK equivalent. Limited by  $T_{j\,\text{max}}.$   $T_{j}$  = 20°C. Maximum duty cycle D=0.5  $^{2)}$  Pulse width  $t_{p}$  limited by  $T_{j,\text{max}}$   $^{3)}$  Proven during verification test. For explanation please read AN - CoolMOS  $^{\text{TM}}$  700V P7.  $^{4)}$   $V_{\text{DClink}}$ =400V;  $V_{\text{DS,peak}}$ <br/> $< V_{\text{(BR),DSS}}$ ; identical low side and high side switch with identical  $R_{\text{G}}$ 



## 3 Electrical characteristics

**Table 4** Static characteristics

Parameter.	0		Values	S	1114	Nata (Tant Candidan
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	700	-	-	V	$V_{GS}$ =0V, $I_D$ =1mA
Gate threshold voltage	V <sub>(GS)th</sub>	2.50	3	3.50	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 0.09 {\rm mA}$
Zero gate voltage drain current	I <sub>DSS</sub>	-	- 10	1 -	μА	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>j</sub> =25°C V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>j</sub> =150°C
Gate-source leakage current incl. Zener diode	I <sub>GSS</sub>	-	-	1	μА	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	0.49 1.03	0.60	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =1.8A, T <sub>i</sub> =25°C V <sub>GS</sub> =10V, I <sub>D</sub> =1.8A, T <sub>i</sub> =150°C
Gate resistance	<b>R</b> <sub>G</sub>	_	10	-	Ω	f=1 MHz, open drain

**Table 5** Dynamic characteristics

Damara dan	Oh a l		Value	s	11	Nata / Tant Candition
Parameter	Symbol	Min.	Min. Typ. Ma		Unit	Note / Test Condition
Input capacitance	C <sub>iss</sub>	-	364	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, <i>f</i> =250kHz
Output capacitance	Coss	-	7	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, f=250kHz
Effective output capacitance, energy related <sup>1)</sup>	C <sub>o(er)</sub>	-	17	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0400V
Effective output capacitance, time related <sup>2)</sup>	C <sub>o(tr)</sub>	-	200	-	pF	I <sub>D</sub> =constant, V <sub>GS</sub> =0V, V <sub>DS</sub> =0400V
Turn-on delay time	t <sub>d(on)</sub>	-	14	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =1.4A, $R_{\rm G}$ =5.3 $\Omega$
Rise time	t <sub>r</sub>	-	5.5	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =1.4A, $R_{\rm G}$ =5.3 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	63	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =1.4A, $R_{\rm G}$ =5.3 $\Omega$
Fall time	t <sub>f</sub>	-	23	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =13V, $I_{\rm D}$ =1.4A, $R_{\rm G}$ =5.3 $\Omega$

Table 6 Gate charge characteristics

Doromotor	Cumbal		Values		Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.		
Gate to source charge	Q <sub>gs</sub>	-	1.6	-	nC	$V_{\rm DD}$ =400V, $I_{\rm D}$ =1.4A, $V_{\rm GS}$ =0 to 10V
Gate to drain charge	$Q_{gd}$	-	3.7	-	nC	$V_{\rm DD}$ =400V, $I_{\rm D}$ =1.4A, $V_{\rm GS}$ =0 to 10V
Gate charge total	Qg	-	10.5	-	nC	$V_{\rm DD}$ =400V, $I_{\rm D}$ =1.4A, $V_{\rm GS}$ =0 to 10V
Gate plateau voltage	V <sub>plateau</sub>	-	4.4	-	V	$V_{\rm DD}$ =400V, $I_{\rm D}$ =1.4A, $V_{\rm GS}$ =0 to 10V

 $<sup>^{1)}</sup>$   $C_{\text{o(er)}}$  is a fixed capacitance that gives the same stored energy as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 400V  $^{2)}$   $C_{\text{o(tr)}}$  is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 400V

# 700V CoolMOS™ P7 Power Device



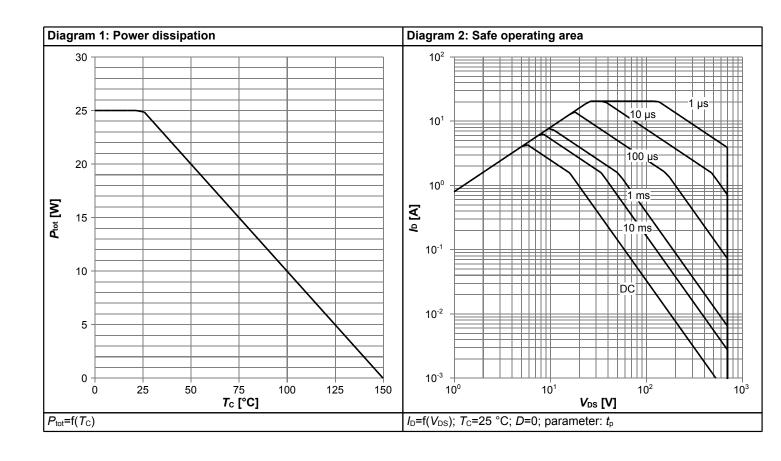


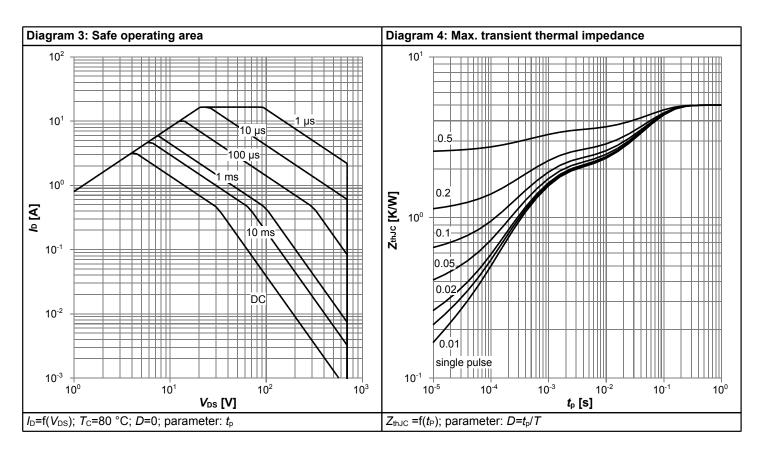
# Table 7 Reverse diode characteristics

Parameter	Cumbal	Values			11	Note / Test Condition
raiailletei	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Diode forward voltage	V <sub>SD</sub>	-	0.9	-	V	V <sub>GS</sub> =0V, I <sub>F</sub> =2.5A, T <sub>j</sub> =25°C
Reverse recovery time	t <sub>rr</sub>	-	190	-	ns	V <sub>R</sub> =400V, I <sub>F</sub> =1.4A, d <i>i</i> <sub>F</sub> /d <i>t</i> =50A/μs
Reverse recovery charge	Qrr	-	0.8	-	μC	V <sub>R</sub> =400V, I <sub>F</sub> =1.4A, d <i>i</i> <sub>F</sub> /d <i>t</i> =50A/μs
Peak reverse recovery current	<i>I</i> <sub>rrm</sub>	-	9	-	Α	V <sub>R</sub> =400V, I <sub>F</sub> =1.4A, d <i>i</i> <sub>F</sub> /d <i>t</i> =50A/μs

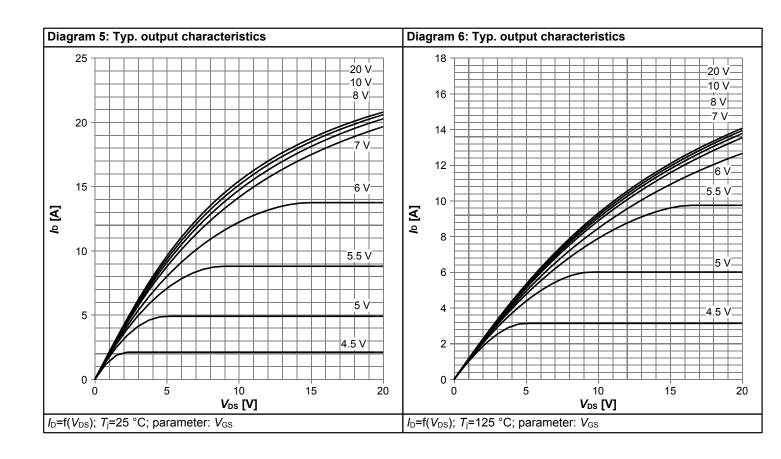


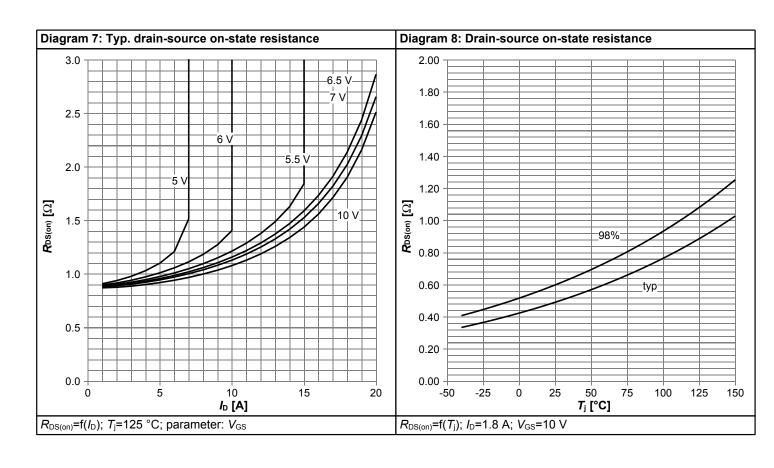
# 4 Electrical characteristics diagrams



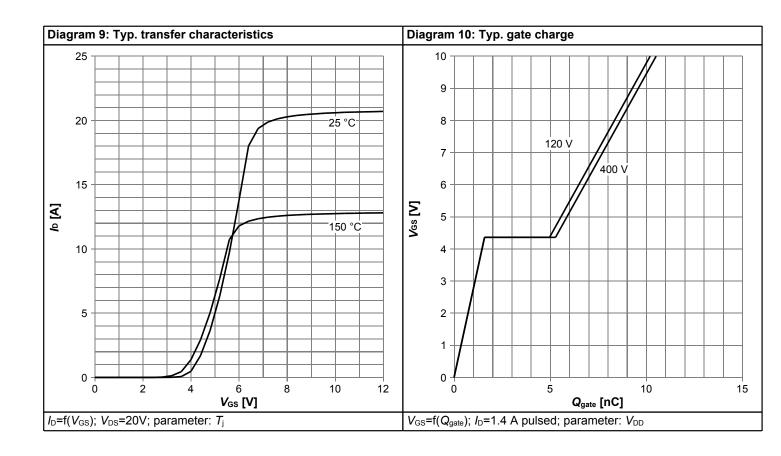


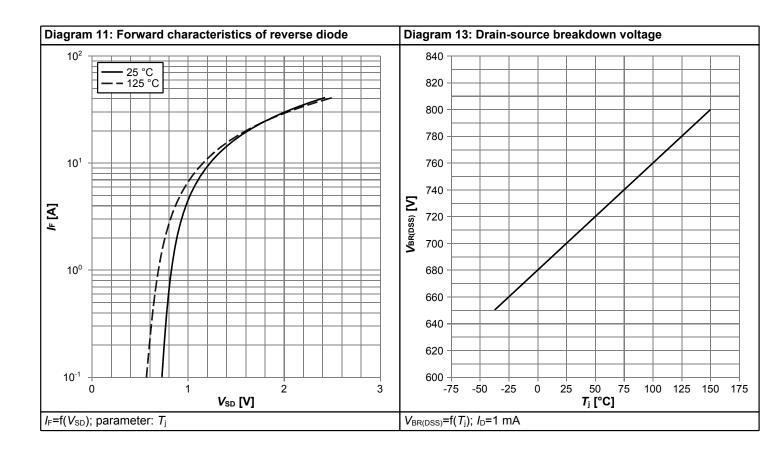




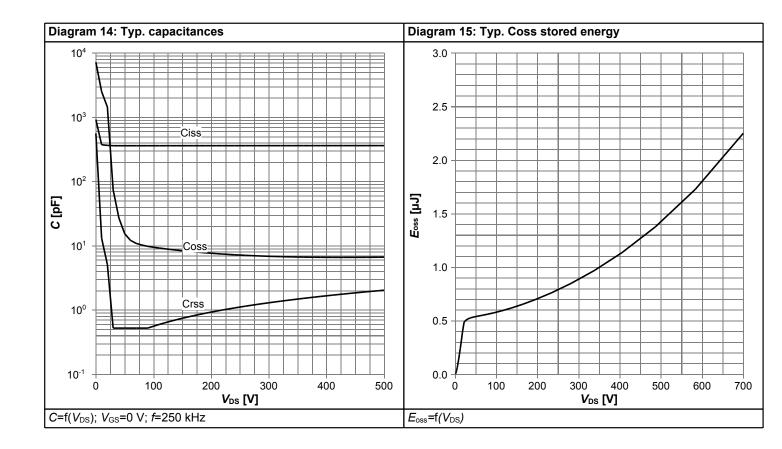














## 5 Test Circuits

**Table 8** Diode characteristics

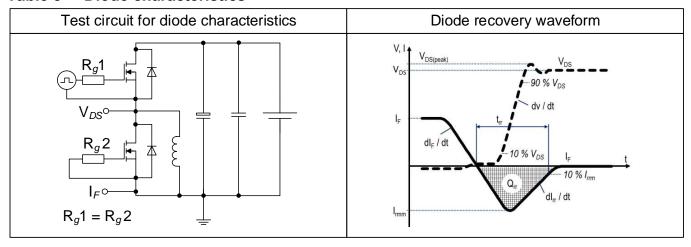
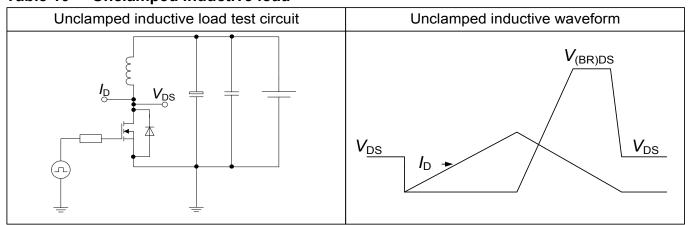


Table 9 Switching times

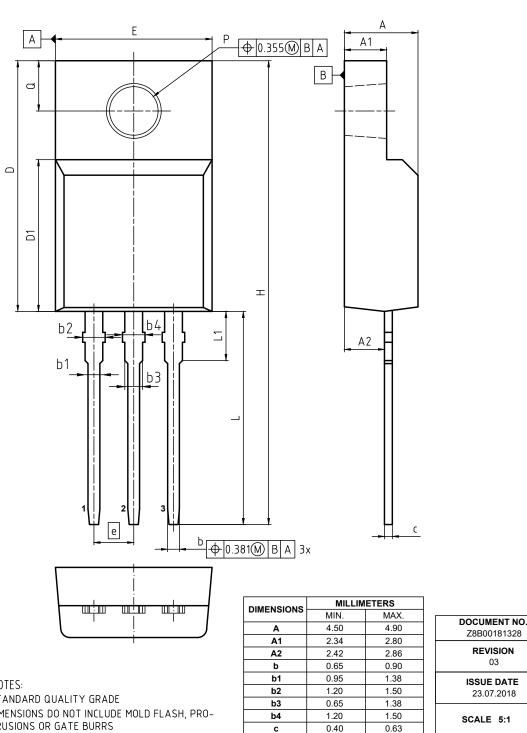


Table 10 Unclamped inductive load





#### **Package Outlines** 6



	NOTES:
(	STANDARD QUALITY GRADE
	DIMENSIONS DO NOT INCLUDE MOLD FLASH, PRO-
1	TRUSIONS OR GATE BURRS

MILLIMETERS						
MIN.	MAX.					
4.50	4.90					
2.34	2.80					
2.42	2.86					
0.65	0.90					
0.95	1.38					
1.20	1.50					
0.65	1.38					
1.20	1.50					
0.40	0.63					
15.67	16.15					
8.97	9.83					
10.00	10.65					
2.	2.54					
28.70	29.75					
12.78	13.75					
2.83	3.45					
3.00	3.38					
3.15	3.50					
	MIN. 4.50 2.34 2.42 0.65 0.95 1.20 0.65 1.20 0.40 15.67 8.97 10.00 2.870 12.78 2.83 3.00					

Z8B00181328						
REVISION 03						
ISSUE DATE 23.07.2018						
SCALE 5:1						
0 1 2 3 4 5mm						
EUROPEAN PROJECTION						

Figure 1 Outline PG-TO 220 FullPAK, dimensions in mm/inches



# 7 Appendix A

## Table 11 Related Links

• IFX CoolMOS™ P7 Webpage: www.infineon.com

• IFX Design tools: www.infineon.com



### **Revision History**

IPA70R600P7S

Revision: 2020-01-27, Rev. 2.2

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2016-10-11	Release of final version
2.1	2018-02-12	Corrected front page text
2.2	2020-01-27	Updated package drawing, symbol ID and product validation

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